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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE					APPLICANT Garo J. Derderian et al.					
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V2	AA	5,377,429	01-1995	Sandhu et al.		341	586			
4	AE	5,480,818	01-1996	Matsumoto et	at.	438	500)			
	AC	5,851,849	12-1998	Comizzoli et a	l.	438	39			
	AE	5,879,459	03-1999	Gadgil et al.		118	715			
	AE	5,908,947	06-1999	Vaartstra		536	42		•	
	AF	6,042,652	03-2000	Hyun et al.		118	74			
	AC	6,139,700	10-2000	Kang et al.		w/	PUF	1		
	AI	6,143,659	11-2000	Leem		438	688			
	A	6,144,060	11-2000	Park et al.		257	3/0			
	A	6,174,377 B1	01-2001	Doering et al.		118	729			
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VIST	Al	JP 61-5515	01-1986	Itou et al.						
1	AL	JP02-371361	12-2002	Japan						
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115	AA	6,174,809 B1	01-2001	Kang et al.		438	682	3	
111	AB	6,203,613 B	03-2001	Gates et al.	•	117	104		
	AC	6,237,529 B1	05-2001	Spahn		118	726		
	AD	6,270,572 B1	08-2001	Kim et al.		117	93		
	ΑE	6,287,965 B1	09-2001	Kang et al.		428	648		
	AF	6,297,539 B1	10-2001	Ma et al.		257	410		
	AG	6,305,314 B1	10-2001	Sneh et al.		18	7231		
	АН	6,419,462	07-2002	Horie et al.		47	394		
	AI	5,885,358	03-1999	Maydan et al.		118	7231	4	
	AJ	6,056,994	05-2000	Paz de Araujo	et al.	427	054		
	AK	5,743,457	04-1998	Benedette et a	l.	233	(33)		
,	AL	5,678,595	10-1997	lwabuchi		137	341		
V	A M	5,564,907	10-1996	Maruyama et a	ıl.	47	25)		
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12	M	5,547,714	08-1996	Huck et al.		427	523			
1	AB	5,150,734	09-1992	Chiba		137	85.3	3		
	AC	5,002,928	03-1991	Fukui et al.			401			
	AD	4,805,552	02-1989	Pagendarm et	al.	118	325	1		
	AE	4,273,291	06-1981	. Muller		239	S33.10			
	AF	3,110,319	11-1963	Arata et al.		137	340			
	AG	4,319,737	03-1982	Waterfield		251	331			
	AH	6,228,563	05-2001	Starov et al.		430	327			
	Al	6,333,268	12-2001	Starov et al.		438	691			
	AJ	4,872,947	10-1989	Wang et al.		216	38			
	AK	5,000,113	03-1991	Wang et al.		1/8	7238			
	AL	5,362,526	11-1994	Wang et al.		427	573	,		
V	A M	5,853,484	12-1998	Jeong		118	715			
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16	AA	5,522,934	06-1996	Suzuki et al.		118	7257	1		
	AB	5,620,523	04-1997	Maeda et al.		118	7251	4		
	AC	5,772,771	06-1998	Li et al.		118	7234			
	AD	6,132,552	10-2000	Donohoe et al.		150	34533	,		
	AE	6,294,026	09-2001	Rolthner et al.		118	715			
	AF	6,453,992 B1	09-2002	Kim		65	256		····	
	AG	5,792,272	08-1998	Van Os et al.		118	723P	-		
	AH	6,677,250	01-2004	Campbell et al.	•	438	758			
	AI	4,392,915	07-1983	Zajac		438	716		•	
	AJ	4,716,852	01-1988	Tsujli et al.		118	720			
	1,,,	4,738,748	04-1988	Kisa		123	212	1		
	AK AL	5,453,124	09-1995	Moslehl et al.		118	215	<b> </b>		
T.	A M	5,500,256	03-1996	Watabe		427	574			
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1/2	AA	5,532,190	07-1996	Goodyear et al	ī. ·	438	7/0			
9	AB	5,556,474	09-1996	Otani et al.		118	723	4		
	AC	5,647,912	07-1997	Kaminishizono	et al	1/8	719	2		
	AD	5,827,370	10-1998	Gu		118	7/5			
	ΑE	5,885,751	03-1999	Weidman et al	•	430	3/5			
	AF	5,983,906	11-1999	Zhao et al.		141	(.1			
	AG	6,050,506	04-2000	Guo et al.		239	278	?		
	АН	6,059,885	05-2000	Ohashi et al.	<u> </u>	118	730	5	•	
	Al	6,113,078	09-2000	Rock		201	2/			
	AJ	6,114,227	09-2000	Leksell et al.		438	584	1		
	AK	6,132,512	10-2000	Horie et al.		1/8	715	=	-	
. /	AL	6,197,119 B1	03-2001	Dozoretz et al.		1/8	715	1	· ·	
	A M	6,426,307 B2	07-2002	Lim		438	778			
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1	AA	6,444,039 B1	09-2000	Nguyen		1/8	715	1	
	AB	5,755,886	05-1998	Wang et al.		118	715	1	
	AC	5,972,430	10-1999	DiMeo et al.		427	213	<b>沙</b>	
	, AD	2004/0083959	05-2004	Carpenter et a	al.	118	715	-	
	AE	2002/0129768	09-2002	Carpenter et a	al.	118	715	1	
	AF	2001/0045187	11-2001	Uhlenbrock		118	715	+	
	AG	2004/0124131	07-2004	Aitchison et a	l.	210	25		1
	ÀН	2002/0164420	11-2002	Derderian et a	al.	427	248.		
	AI	2003/0194862	10-2003	Mardian et al.		438	680	\$	
	AJ	2003/0045098	03-2003	Verhaverbeke	et al.		689	<del>                                     </del>	
	AK	2002/0155632	10-2002	Yamazaki et a	al.	438	29		
	AL	2003/0033980	02-2003	Campbell et a	ı <b>l.</b>	118	715		
17	A M	2004/0144310	07-2004	Campbell et a	ı <b>l.</b>	118	715	1	· ·
	AN	2003/0215569	11-2003	Mardian et al.		427	248.		
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4	_ AA	6,071,572	06-2000	Mosely et al.		427	570	3			
	AB	6,200,893 B1	03-2001	Sneh		437	685				
	AC	6,602,784 B2	08-2003	Sneh		438	680				
	AD	6,458,416 BI	10-2002	Derderian et al.		427	30/		-		
$\square$	AE	6,627,260 B2	09-2003	Derderian et al.		427	570				
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